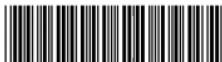


<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10550324	TACHIKAWA ET AL.
<b>Examiner</b>	<b>Art Unit</b>	
Christopher L Chin	1641	

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST search	3/30/08	CC
STN-CAS search	3/30/08	CC
EAST search	11/5/08	CC
EAST and STN-CAS search	6/20/09	CC
EAST search	9/29/09	CC

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
Same as above		9/29/09	CC

	/C. L. C./ Primary Examiner, Art Unit 1641
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